

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
347	236-237, 246-247	6/13/2005	HP

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/13/2005	HP